SAR_NOVAT_036_07002_X950D_FCC





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This addendum supplements the SAR Test Report SAR_NOVAT_036_07002_X950D_FCC, section 8.

1. Test Settings

The device was tested with the following UE categories:

E-DCH Category 5

Maximum number of E_DCH codes transmitted = 2

Minimum spreading factor = SF2

TTI = 10ms only

Maximum number of bits of an E-DCH transport block transmitted = 20000

Data Rate = 2 Mbps

HS-DSCH Category 8

Maximum number of HS-DSCH codes received = 10

Minimum inter-TTI interval = 1

Maximum number of bits of an E-DCH transport block received = 14411

Total number of soft channel bits = 134400

Data Rate = 7.21 Mbps

Active Physical Channels:

DPCCH, DPDCH, HS-DPCCH, E-DPCCH, and E-DPDCH $_{\rm n}$ vary according to the sub-tests defined in the SAR Test Report.

Implementation of MPR form Qualcomm (the Chipset supplier of the EUT) is designed according to 3GPP TS 25.101 V6.14.0 (2006-12) Section 6.2.2 UE maximum output power with HS-DPCCH and E-DCH. Relevant power scaling is designed according to 3GPP TS 25.214 V6.11.0 (2006-12) Section 5.1.2.6 Maximum and minimum power limits.



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2. Sub-test Conducted Output Power

Sub-test parameters were setup using the CMU200 with engineering firmware installed. Some of the parameters that define the sub-tests could not be set directly. To insure proper configuration, procedures were followed from a supplemental operation manual, provided by Rhode & Schwarz. Refer to the CMU WCDMA Supplement V4x50.

FDDV		
Sub-test	Channel	dBm
1	4132	21.66
	4175	20.93
	4233	20.91
2	4132	21.16
	4175	20.87
	4233	22.60
3	4132	21.34
	4175	21.80
	4233	21.68
4	4132	21.49
	4175	20.96
	4233	20.01
5	4132	22.47
	4175	22.70
	4233	22.57

FDDII		
Sub-test	Channel	dBm
1	9262	22.66
	9400	22.62
	9538	22.43
2	9262	22.27
	9400	21.81
	9538	22.39
3	9262	21.65
	9400	21.37
	9538	21.60
4	9262	21.71
	9400	21.27
	9538	21.62
5	9262	23.35
	9400	23.87
	9538	23.45

The highlighted sub-tests represent the sub-test with the highest conducted power and the sub-test used for the SAR measurements.